

Non-Linear Junction Detection Scan Report

(NLJD)

Client Information

Name: Sandra Walters
Year of Birth: 1960
Age: 66
Sex: Female
Height: 5 ft 6 in
Weight: 140 lbs
Place of Birth: Akron, Ohio, USA
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Contact Phone: 330-571-4895
Location of Testing: Fort Wayne, Indiana
Date of Testing: May 2, 2026
Case Reference: 050226SW66

Introduction

This report documents the findings of a Non-Linear Junction Detection (NLJD) scan conducted by Cosmic Clarity Connections LLC on May 2, 2026, in Fort Wayne, Indiana. The assessment was performed at the request of the client to evaluate the presence of electronic semiconductor junctions in proximity to specific anatomical regions of the body.

A Non-Linear Junction Detector identifies the presence of semiconductor materials by transmitting a radio frequency signal and analyzing the harmonic responses returned. Electronic components containing semiconductor junctions produce a characteristic second-harmonic response, while corroded or naturally occurring metallic junctions tend to produce a stronger third-harmonic response. This methodology is screening and investigative in nature and does not constitute a medical diagnosis.

Instrumentation

The following instrumentation was utilized during this assessment:

- EDD-24XT Non-Linear Junction Detector — an English-manufactured device that detects semiconductor junctions through analysis of second harmonic (semiconductor) and third-harmonic (corrosive junction) responses, enabling differentiation between genuine electronic components and naturally occurring metallic or corroded junctions.

- Spectrum Analyzer — used to monitor and characterize the ambient radio frequency environment during testing in order to distinguish localized responses from background signals.

Assessment Methodology

1. The client was positioned to allow systematic access to both the anterior and posterior aspects of the body.
2. The EDD-24XT detector was calibrated and operated in accordance with the manufacturer's specifications prior to and during the assessment.
3. Discrete anatomical regions were surveyed individually, with the detector positioned in close proximity to the surface of each region.
4. Second harmonic (semiconductor) and, where present, third harmonic (corrosive junction) responses were recorded as a relative percentage for each region assessed.
5. Each region exhibiting a positive response was reassessed to evaluate the reproducibility and stability of the detected response.

Client-Provided Background (Optional Section)

The client elected to participate in this assessment voluntarily and reported concerns consistent with anomalous health incidents. No additional medical or historical background was provided for inclusion in this report.

Response Strength Classification

Detected responses are classified according to the following relative strength tiers:

Response Range	Classification
0–25%	Minimal or Inconclusive nonlinear activity
26–60%	Moderate Probability of semiconductive response
61–100%	Strong-Significant semiconductor-type response

NLJD Scan Findings

The following table documents the second-harmonic (semiconductor) and third-harmonic (corrosive junction) responses recorded at each anatomical region assessed. A dash (—) in the corrosive junction column indicates no elevated third-harmonic response was recorded at that region.

Anatomical Region	Semiconductor (2H)	Corrosive Junction (3H)	Notes
Anterior Aspect			
Right TMJ Region	20%	—	Minimal or Inconclusive nonlinear activity

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Anatomical Region	Semiconductor (2H)	Corrosive Junction (3H)	Notes
Nasal Dorsum Region	20%	—	Moderate Probability of semiconductive response
Left TMJ Region	40%	—	Minimal or Inconclusive nonlinear activity
Anterior Base of Neck Region	20%	—	Minimal or Inconclusive nonlinear activity
Right Shoulder Region	40%	—	Minimal or Inconclusive nonlinear activity
Right Apex Region	60%	—	Moderate Probability of semiconductive response
Left Apex Region	60%	—	Moderate Probability of semiconductive response
Left Shoulder Region	70%	—	Strong-Significant semiconductor-type response
Right Lateral Torso	60%	—	Moderate Probability of semiconductive response
Left Lateral Torso	80%	—	Strong-Significant semiconductor-type response
Upper Abdomen Midline Region	40%	—	Moderate Probability of semiconductive response
Right Lateral Hip Region	25%	—	Minimal or Inconclusive nonlinear activity
Left Lateral Hip Region	60%	—	Moderate Probability of semiconductive response
Left Lower Quadrant Abdominal Region	60%	—	Moderate Probability of semiconductive response
Right Quadricep Region	70%	—	Strong-Significant semiconductor-type response
Left Quadricep Region	25%	—	Minimal or Inconclusive nonlinear activity
Posterior Aspect			
Occipital Parietal Region	50%	—	Moderate Probability of semiconductive response
Mid Lower Occipital Region	55%	—	Moderate Probability of semiconductive response
Left Temporal Region	40%	—	Moderate Probability of semiconductive response
Base of Neck Region	75%	—	Strong-Significant semiconductor-type response
Left Scapular Region	60%	—	Moderate Probability of semiconductive response

Anatomical Region	Semiconductor (2H)	Corrosive Junction (3H)	Notes
Right Scapular Region	70%	—	Strong-Significant semiconductor-type response
Lower Lumbar Region	80%	—	Strong-Significant semiconductor-type response

Summary

A total of 22 anatomical regions exhibited a positive nonlinear junction response during this assessment, distributed across both the anterior and posterior aspects of the body. Several regions produced strong second-harmonic responses in the 61–100% range, consistent with a semiconductor-type response. No regions exhibited elevated third-harmonic (corrosive junction) activity.

These results are preliminary indicators only. They do not verify the presence of electronic devices, implants, or foreign materials, and are intended to identify regions warranting further analysis using corroborative methodologies.

Interpretation

The EDD-24XT detects semiconductor junctions by analyzing the harmonic content of the returned signal. A strong second-harmonic response in the 61–100% range is characteristic of a semiconductor-type junction, such as those found in electronic components. A pronounced third-harmonic response, by contrast, is more commonly associated with corroded or naturally occurring metallic junctions and can also arise from environmental factors.

Where both second- and third-harmonic responses are elevated at the same region, interpretation is more complex, as the signature may reflect a combination of junction types. The findings documented in this report are non-diagnostic and reflect only the conditions and instrumentation present at the time of testing. Correlation with imaging studies and assessment within a controlled environment are recommended for validation.

Privacy and Confidentiality Notice

The names and informational history of participants will not be disclosed to any source without written consent from the participant. Data such as age, gender, positive or negative result, and similarities between participants may be compiled in the form of an aggregated, anonymized survey. This report and its findings are confidential and intended solely for the use of the named client.

Disclaimer

This report reflects the results of a preliminary Non-Linear Junction Detection screening and is investigative in nature. It does not constitute a medical evaluation, diagnosis, or treatment recommendation, and should not be interpreted as confirming the presence of any electronic device, implant, or foreign material within the client's body.

To further investigate these findings, correlative imaging studies — such as X-ray, high-resolution ultrasound, MRI, or computerized tomography (CT) — are recommended to evaluate whether any physical material is present at the regions of interest. Additionally, re-assessment within a controlled environment, such as a Faraday cage or anechoic chamber, may assist in isolating the client from ambient sources and determining whether detected responses persist.

Cosmic Clarity Connections LLC makes no representation or warranty, express or implied, regarding the cause or origin of any detected response. Any further interpretation should be undertaken in consultation with appropriately qualified medical and technical professionals.

Investigator Biography

Jesse Beltran is the President and Technical Specialist of Cosmic Clarity Connections LLC, a firm specializing in technical surveillance countermeasures (TSCM), electromagnetic signal detection, frequency analysis, and related investigative methodologies. He has conducted preliminary radio frequency testing and field investigations since 2010.

His professional background includes training in Network Computer Architecture, proprietary programming, and participation in the Mathematics, Engineering, Science Achievement (MESA) program through the University of California, Davis. Mr. Beltran is also a retired professional firefighter and paramedic, bringing extensive field experience in safety, emergency response, and investigative procedures.

He holds certifications in technical surveillance countermeasure protocols and continues to conduct investigative research and testing related to radio frequency detection and associated technologies.

Prepared By



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